Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/086,036	BEAN, JAMES	
Examiner	Art Unit	
lude I lean-Gilles	2143	

	SEARCHED		
Class	Subclass	Date	Examiner
709	223-225	3/27/2006	JG
705	10, 14	3/27/2006	JG
707	6	3/27/2006	JG
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
		<del>.</del>		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
PAM tool: Effective Filing Date Double Patenting	3/27/2006	JG
EAST tool: USPAT EPO JPO DERWENT	3/27/2006	JG
Internet: google.com onelook.com IEEE NPLs	3/27/2006	JG
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